



Low-energy event excess in SuperCDMS HVeV detectors

Valentina Novati on behalf of the SuperCDMS collaboration

Northwestern



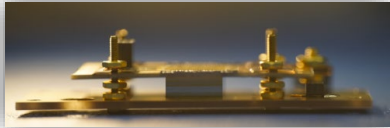
Twitter icon @SuperCDMS

supercdms.slac.stanford.edu

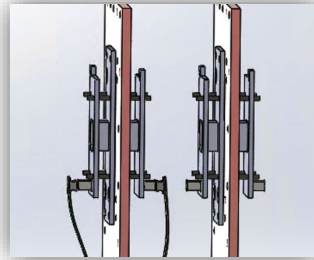
Northwestern

Outline

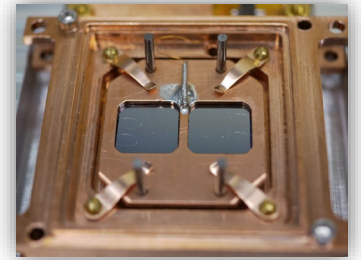
- SuperCDMS HVeV detector description
- Comparison between 0V and HV background with HVeV R2 data
- A coincidence measurement with HVeV R3 data
- Detector holder improvement for HVeV R4



HVeV R2



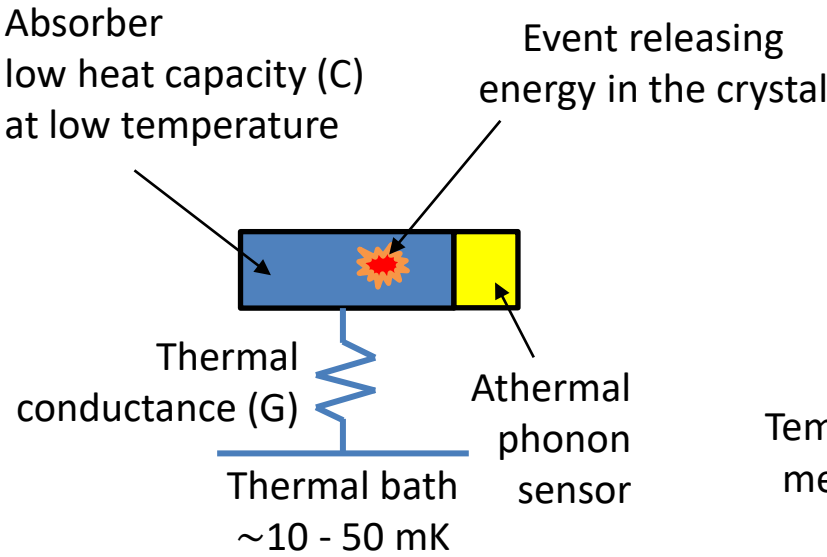
HVeV R3



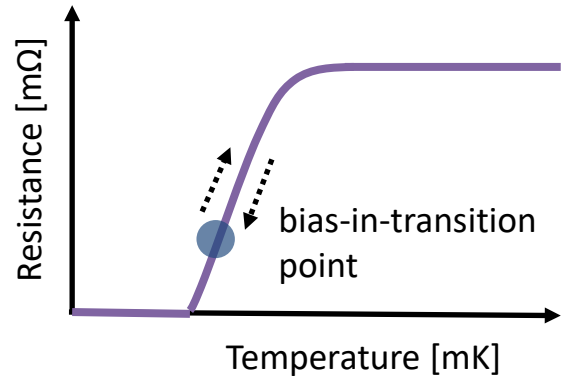
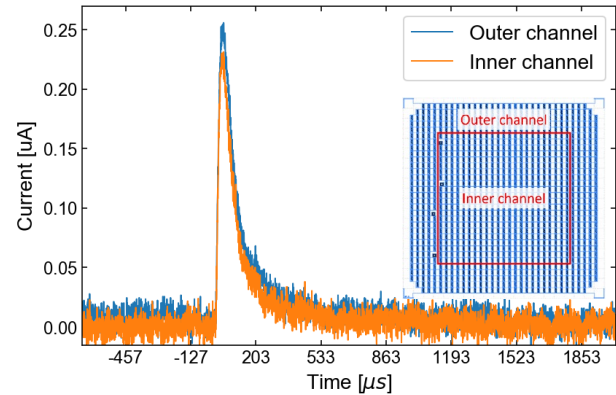
HVeV R4



Calorimetric technique



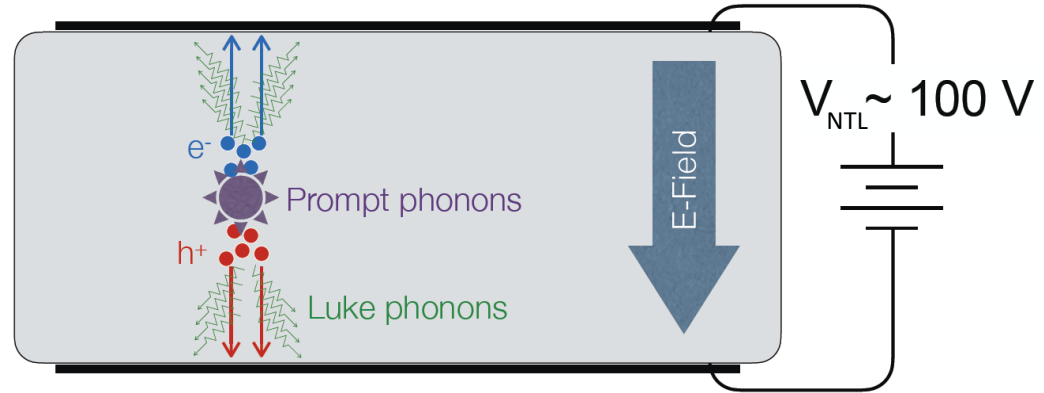
Temperature variations are measured with transition-edge sensors (TES)



Neganov-Trofimov-Luke effect

Charge signals are amplified with an electric field across the crystal

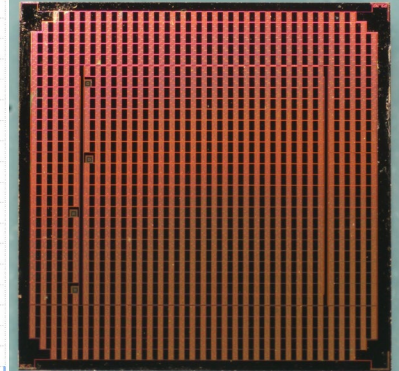
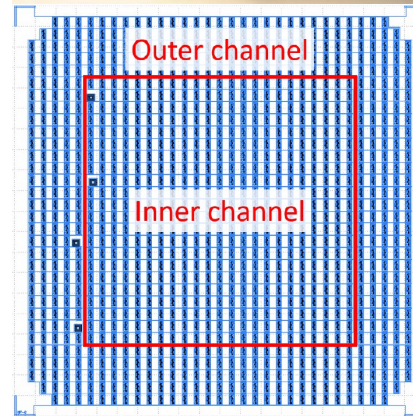
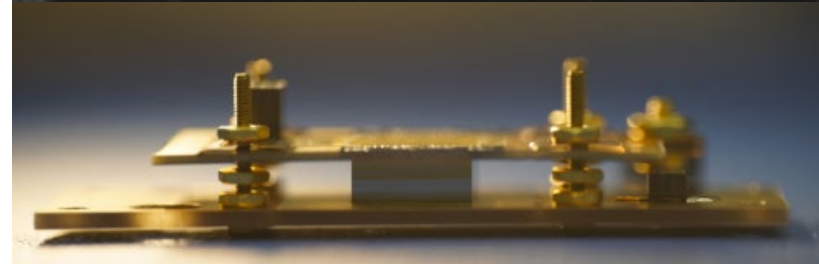
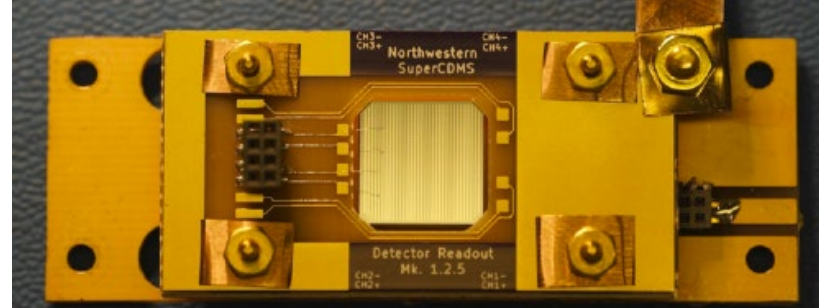
$$E_{\text{total}} = E_{\text{recoil}} \left(1 + \frac{e \cdot Y \cdot V_{\text{NTL}}}{\epsilon_{\text{eh}}} \right)$$



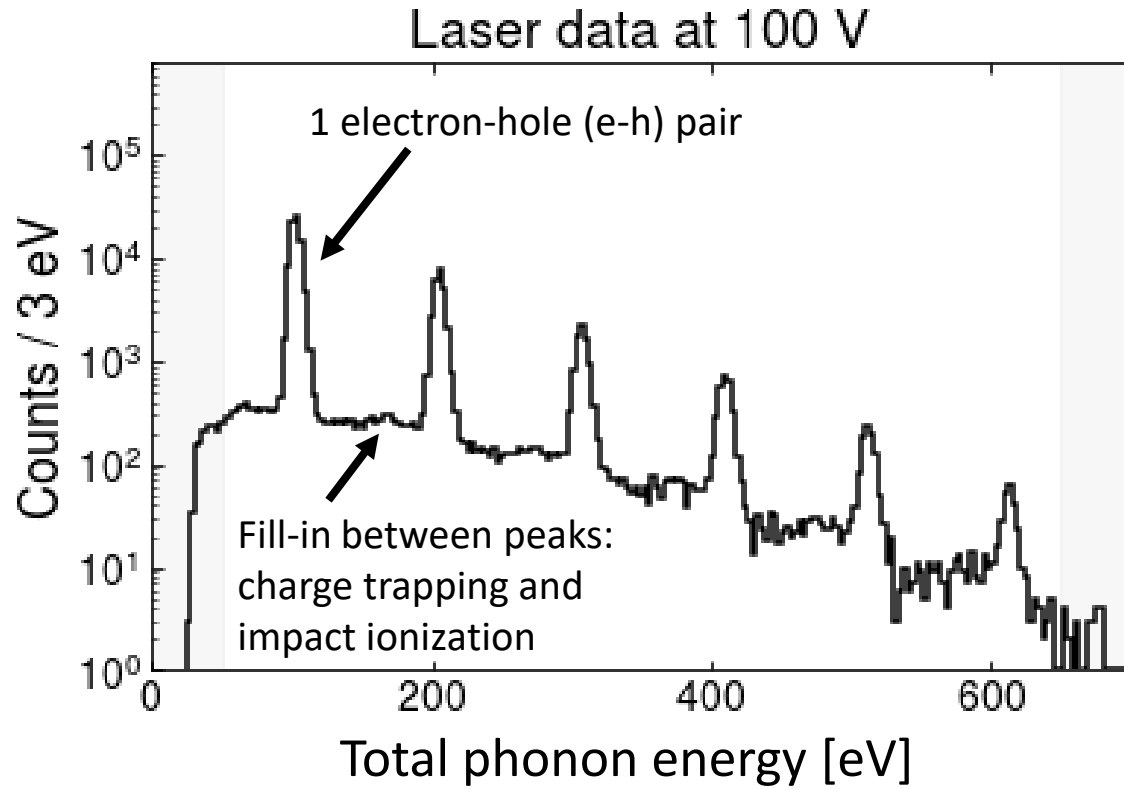
B. S. Neganov and V. N. Trofimov, *Otkryt. Izobret.*, 146, 215 (1985)
 P. N. Luke, *J. Applied Phys.* 64,6858 (1988)

HVeV detectors

- 0.93 g silicon crystal
- 2 channels of TES-arrays
 - Inner and outer channel
 - Same sensor area – same gain
- Aluminium grid on the back of the detector to apply the NTL bias
- Crystal clamped between two PCB boards
 - Provides electrical and thermal connection
 - 4 spring mechanisms with ~ 10 -70 grams each

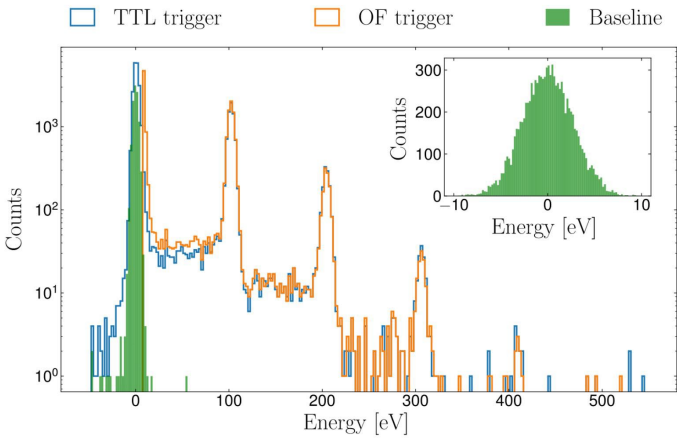


Single electron-hole pair sensitivity



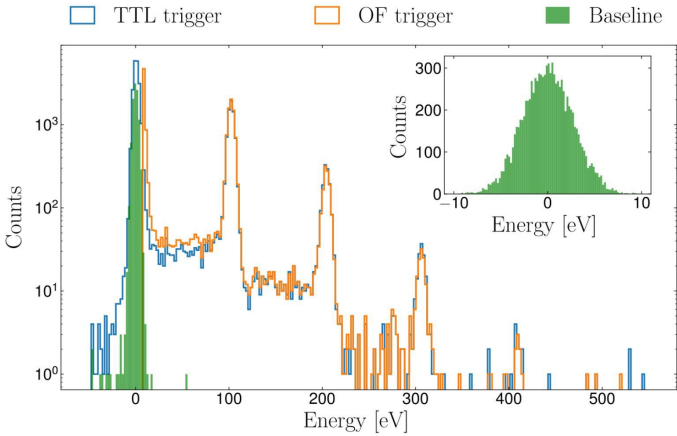
D. W. Amaral et al., Phys. Rev. D 102, 091101(R), 2020
F. Ponce, et al., Phys. Rev. D 101, 031101(R), 2020

HVeV detectors

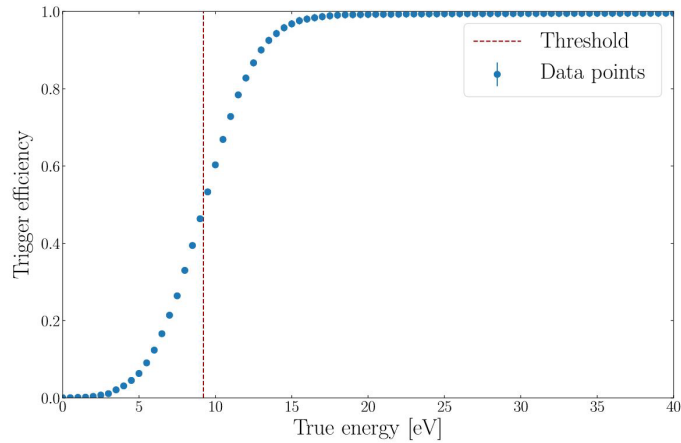


- 2.7 eV baseline resolution

HVeV detectors

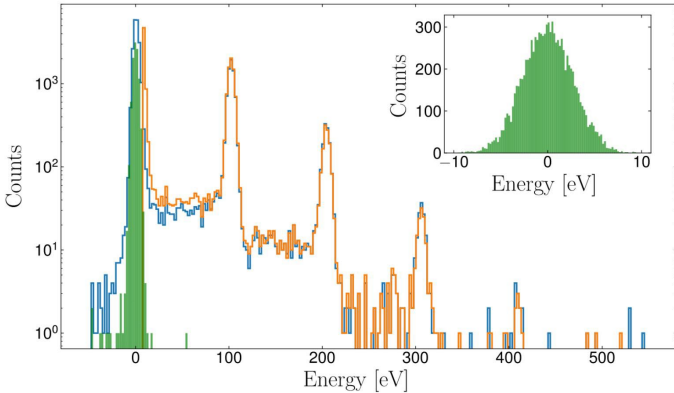


- 2.7 eV baseline resolution
- 9.2 eV threshold



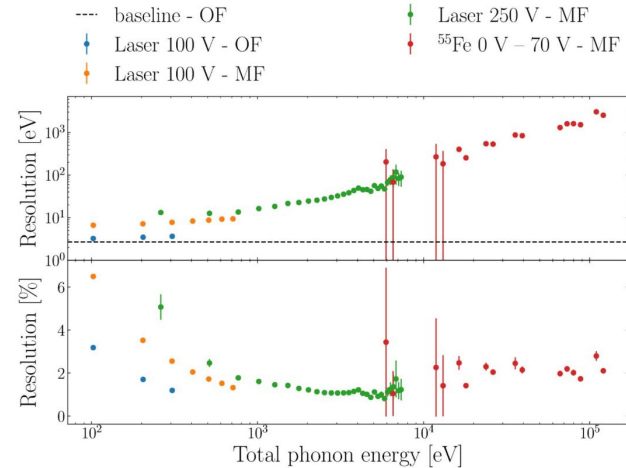
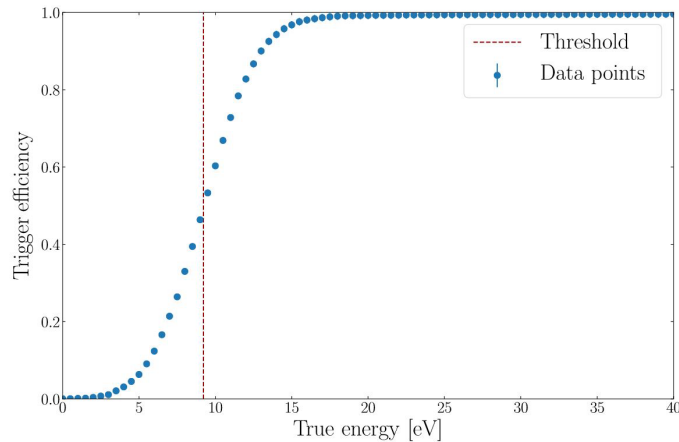
HVeV detectors

□ TTL trigger
 □ OF trigger
 ■ Baseline



- 2.7 eV baseline resolution
- 9.2 eV threshold
- First eV-scale detector reaching up to hundreds of keV (4 order of magnitude)
- Energy resolution < 5 % over the full energy range

best in class!



Run 2 - Northwestern laboratory

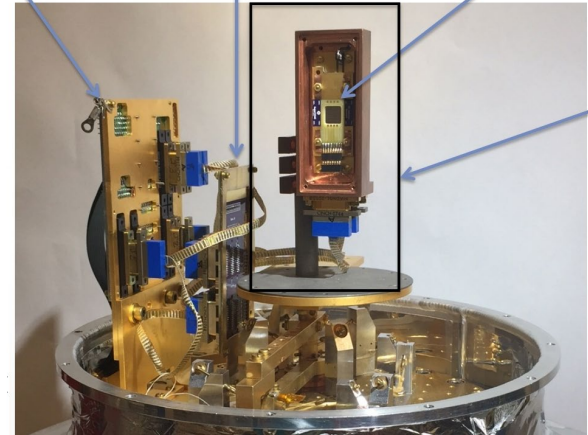
- Surface laboratory at Northwestern University (Evanston, IL)
- No passive or active shielding
- Detector operated at 50 - 52 mK in an Adiabatic Demagnetization Refrigerator (ADR)



Readout board
SQUIDS
(~1.3K)

GGG heat sinking
(~300mK)

Detector Box
(~50mK)

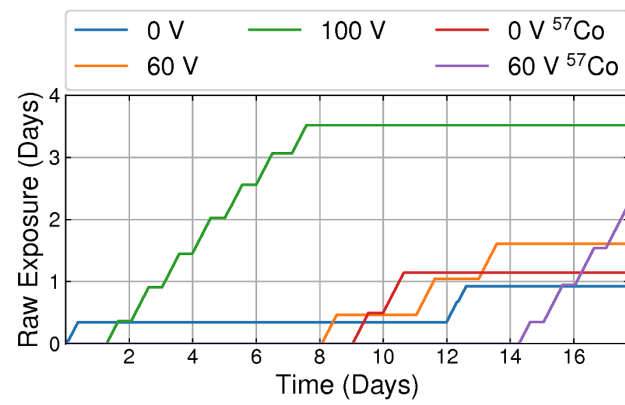
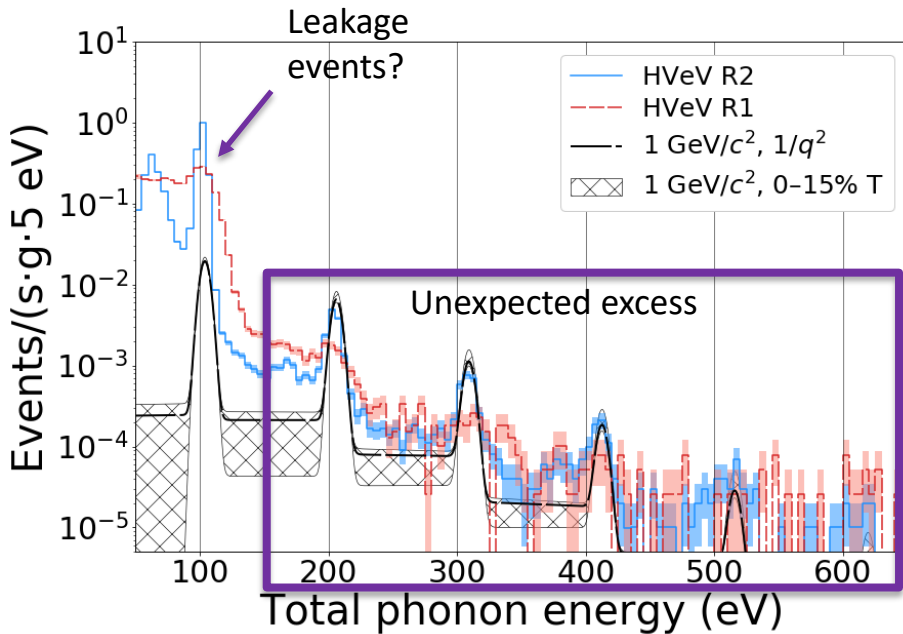


Nb Can
location

Z. Hong *et al.*, NIMA, 963, 163757, 2020
D. W. Amaral *et al.*, Phys. Rev. D 102, 091101(R), 2020

Run 2 – data

Data taken at 0 V, 60 V and 100 V



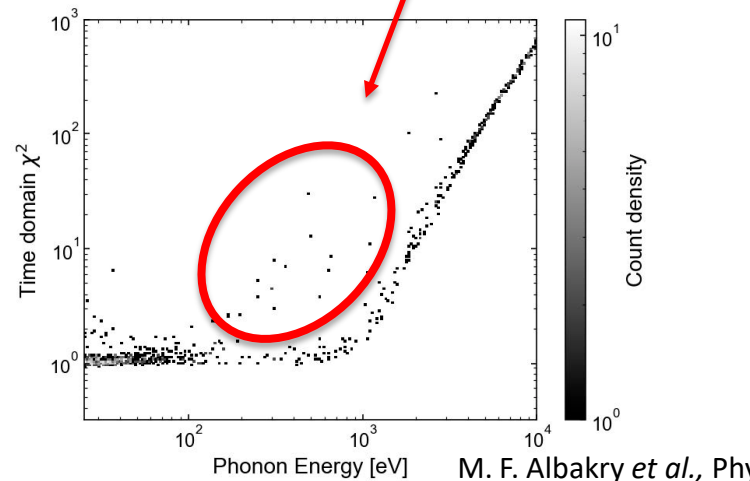
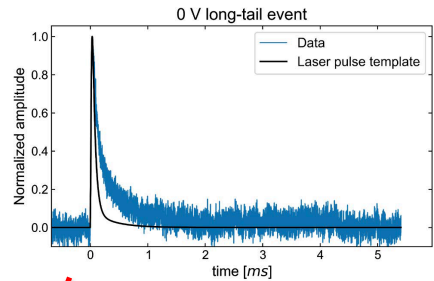
Compatible background between HVeV R1 and R2

→ dedicated comparison between 0V and HV data

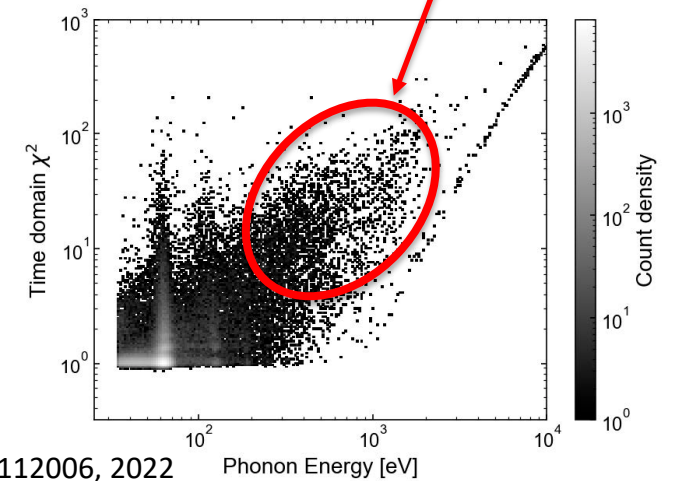
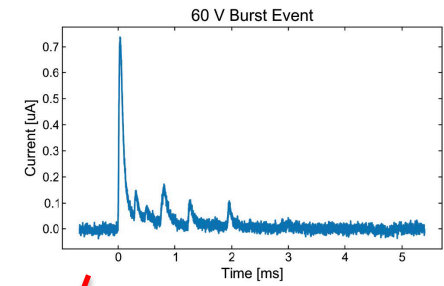
D. W. Amaral *et al.*, Phys. Rev. D 102, 091101(R), 2020

Run 2 – 0V-HV comparison

Long-decay-time events in the 0 V data: longer tail than laser-events



Burst events in the high voltage (HV) data: Primary event followed by single-photon secondary events



M. F. Albakry *et al.*, Phys. Rev. D 105, 112006, 2022

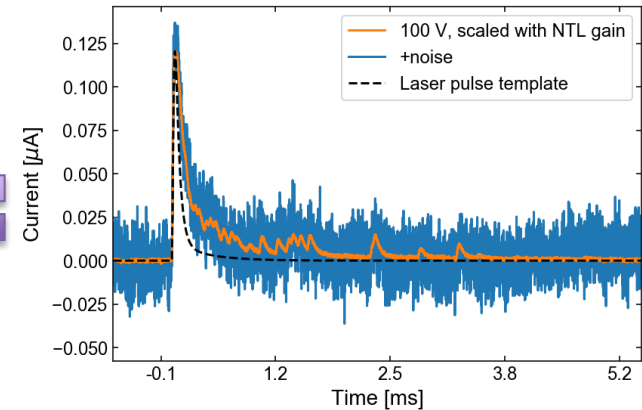
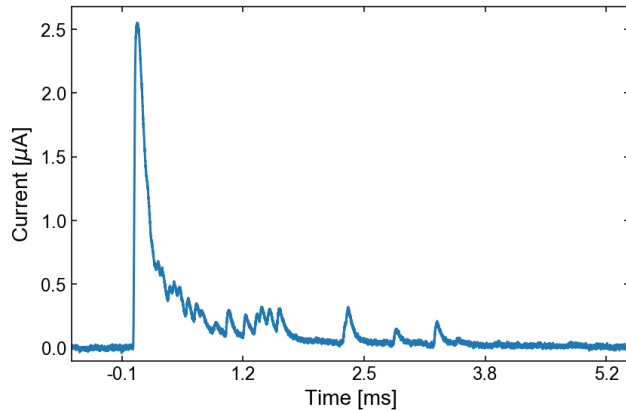
Run 2 – 0V-HV comparison

$$E_{\text{total}} = E_{\text{recoil}} \left(1 + \frac{e}{\epsilon_{\text{eff}}} V_{\text{NTL}} \right) = E_{\text{recoil}} G_{\text{NTL}}$$

energy to create an electron-hole pair (ϵ_{eh})
divided by the ionization yield (Y)

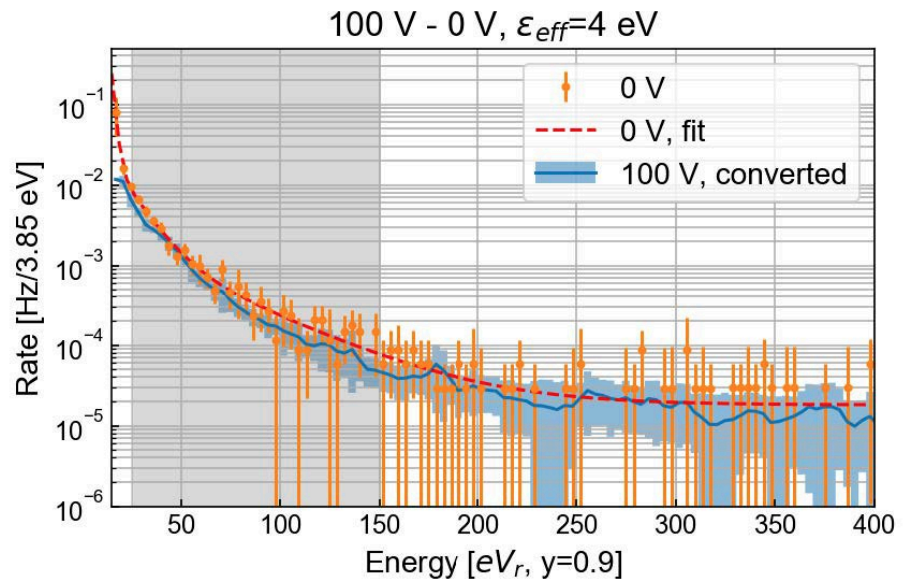
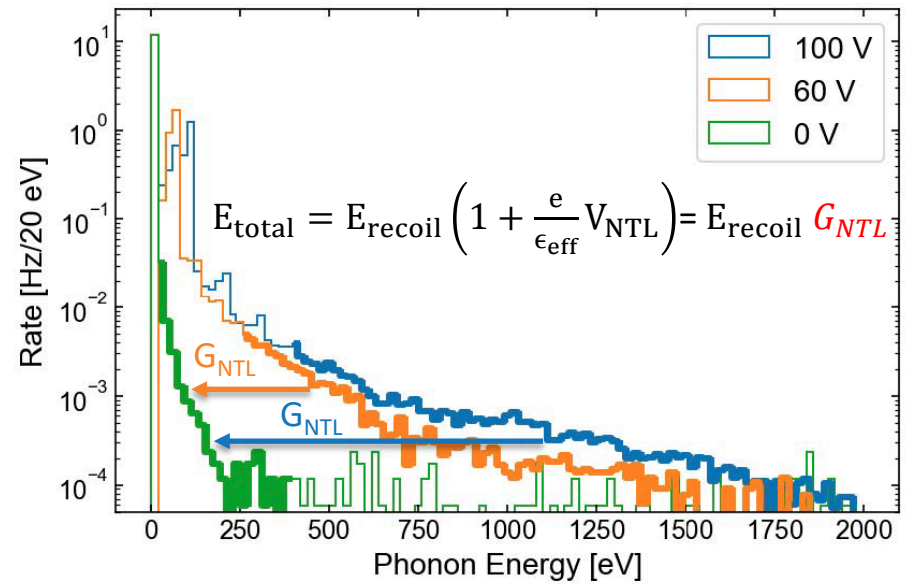
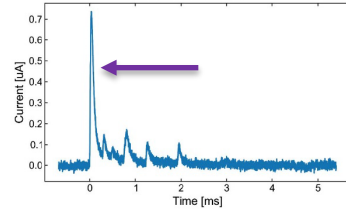
Neganov-Trofimov-Luke
voltage

Neganov-Trofimov-Luke
gain



M. F. Albakry *et al.*, Phys. Rev. D 105, 112006, 2022

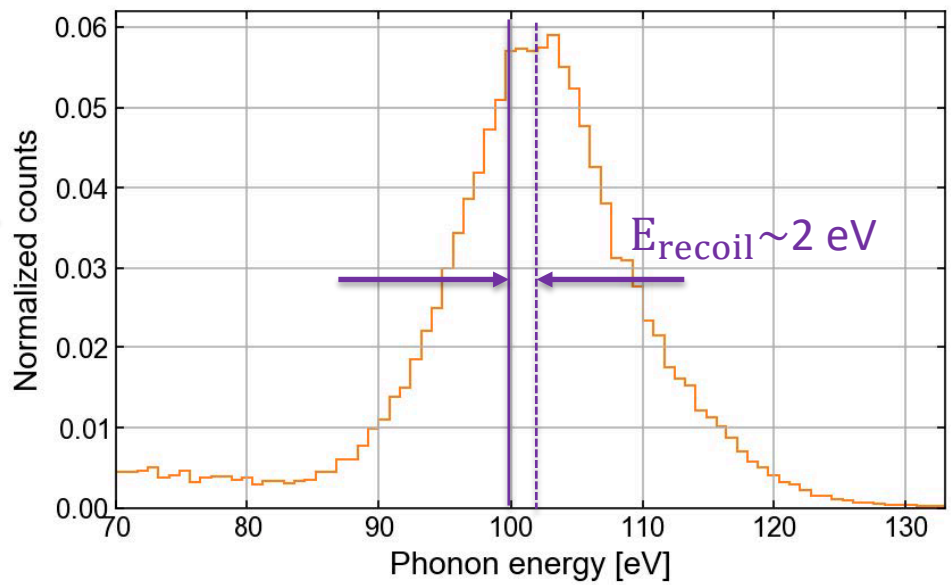
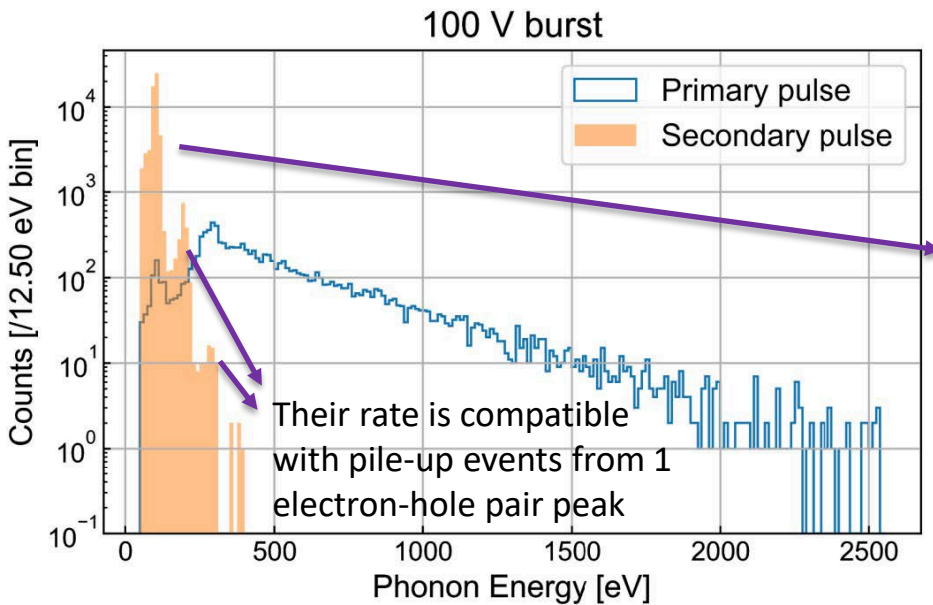
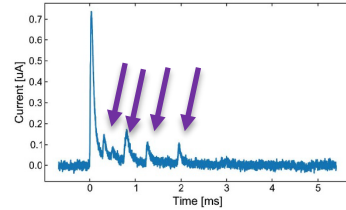
Run 2 – primary events



There is compatibility between the primary events in HV and 0V mode assuming $\epsilon_{\text{eff}} \sim 4\text{-}5$ eV

M. F. Albakry *et al.*, Phys. Rev. D 105, 112006, 2022

Run 2 – secondary events



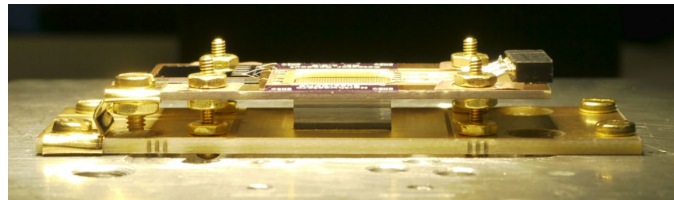
Secondary events have an energy of ~ 2 eV

M. F. Albakry *et al.*, Phys. Rev. D 105, 112006, 2022

Run 2 – 0V comparison

Burst events and luminescence from the SiO₂ present in PCB have:

- Compatible energies
- Compatible relaxation time



The PCB holder provides both:

- detector thermalization
- electrical contacts

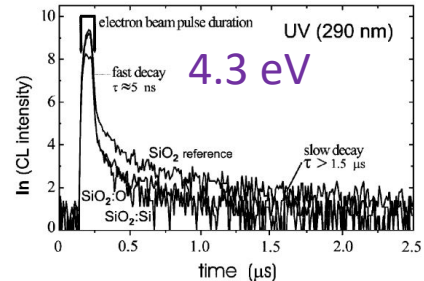
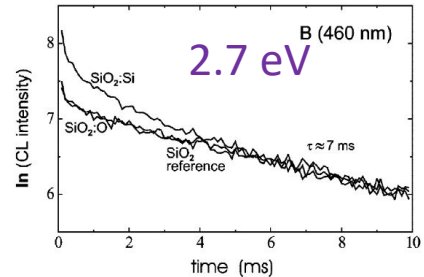
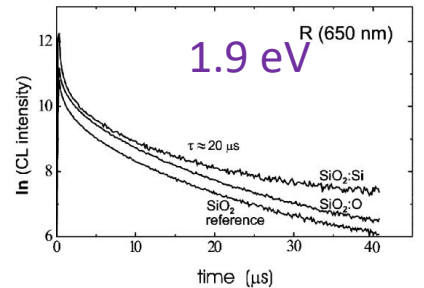
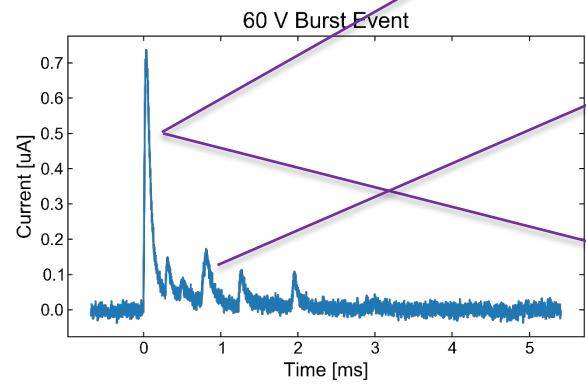
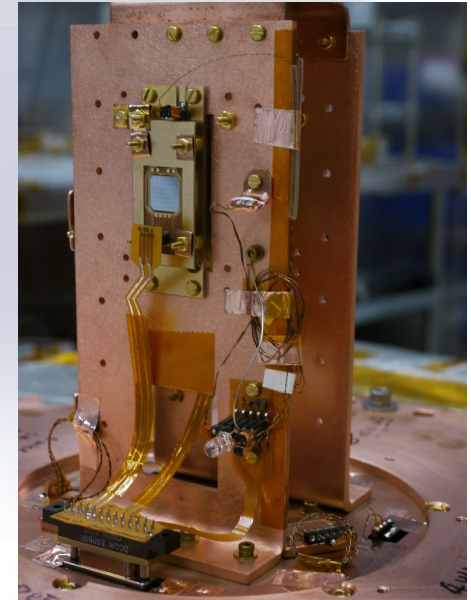
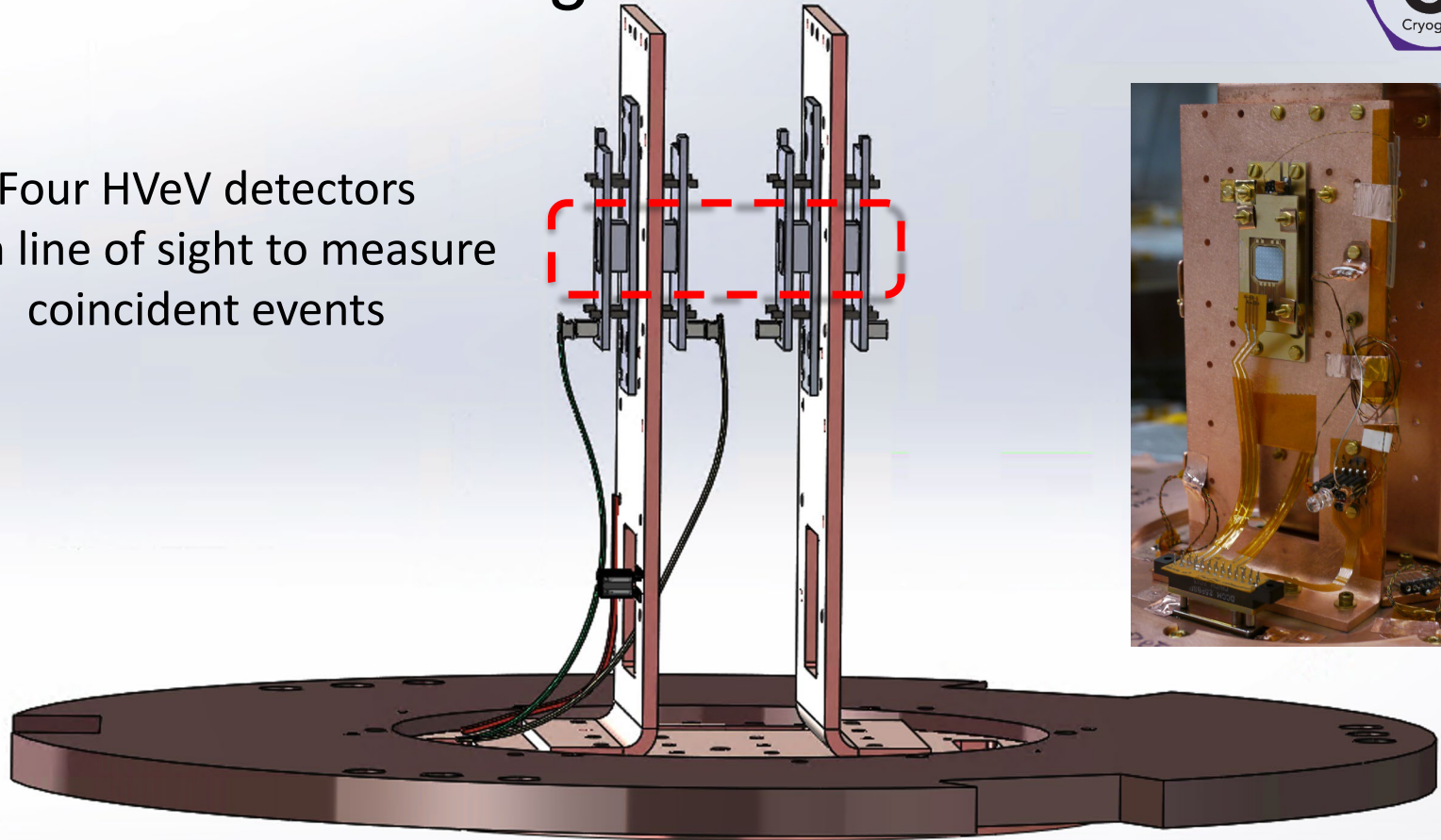


Fig. 3. Decay kinetics of the red R, blue B and UV luminescence in thin SiO₂ films partially doped with Si⁺ and O⁺ ions and excited by a pulsed electron beam at liquid nitrogen temperature (LNT).

M. F. Albakry *et al.*, Phys. Rev. D 105, 112006, 2022
A.N. Trukhin *et al.*, J. Non Cryst. Solids 331 (2003) 91

Run 3 – detector configuration

Four HVeV detectors
with line of sight to measure
coincident events



Run 3 – new measurement at the NEXUS facility

Northwestern EXperimental Underground Site (NEXUS) facility at Fermilab (Batavia, IL)

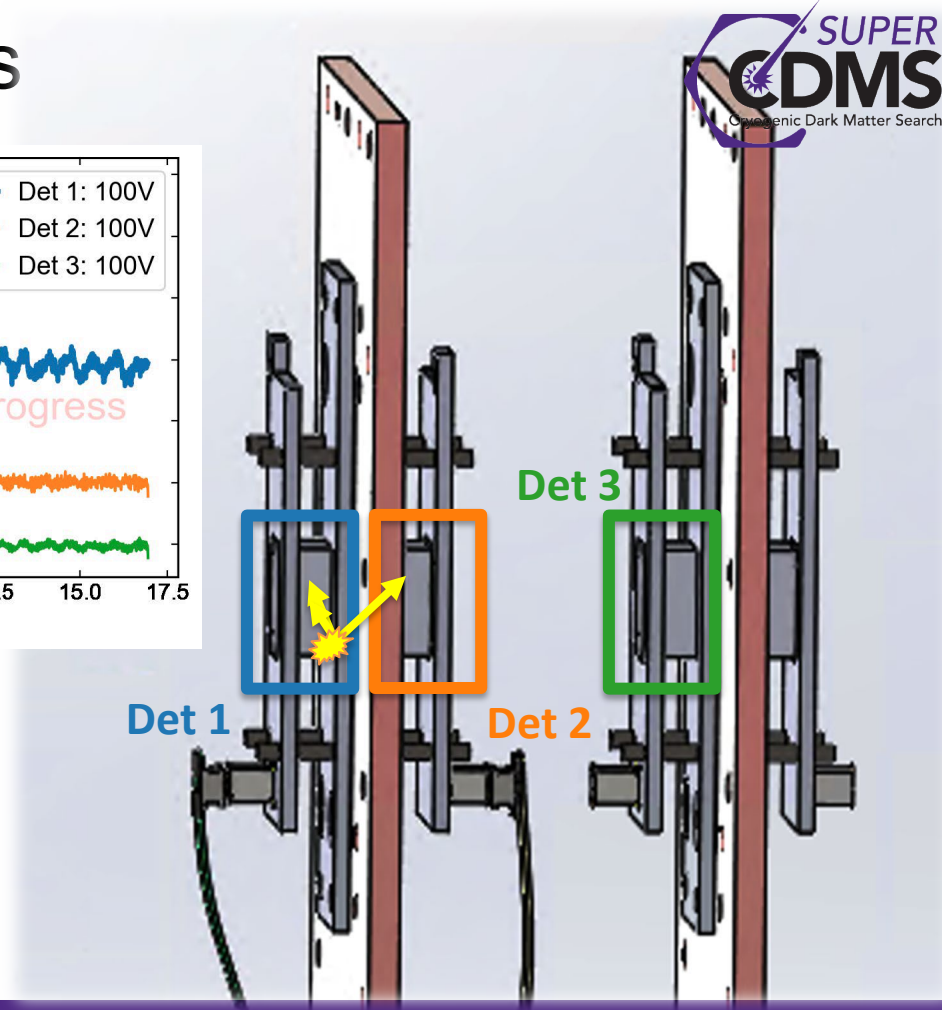
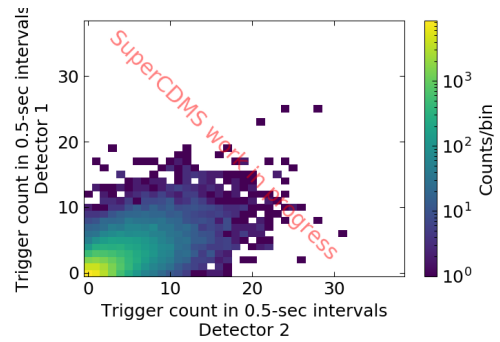
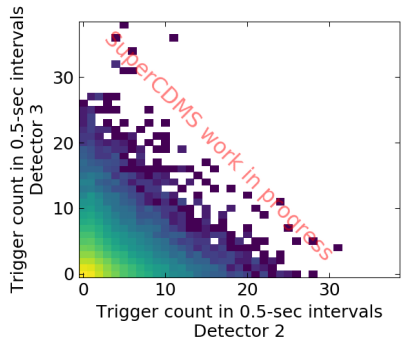
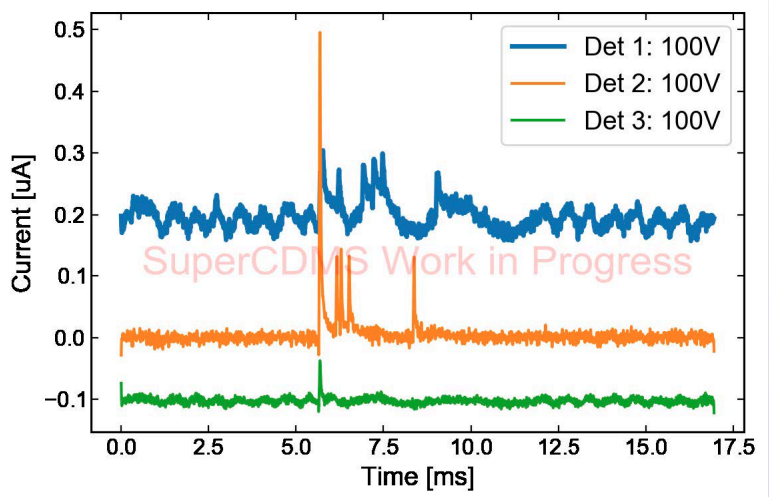
Dry dilution refrigerator from Cryoconcept:

- base temperature ~ 9 mK
- located in the MINOS hall
 - 107 m underground (~ 300 mwe)
- Internal lead shield + movable external lead castle
- Vibration reduction via pulse-tube decoupling



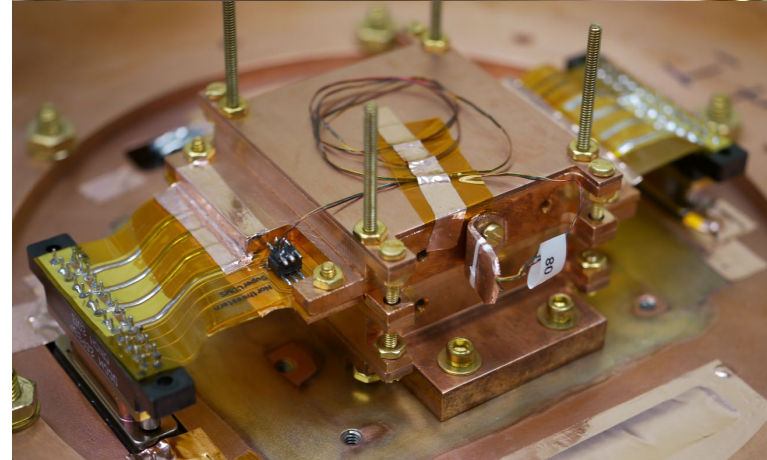
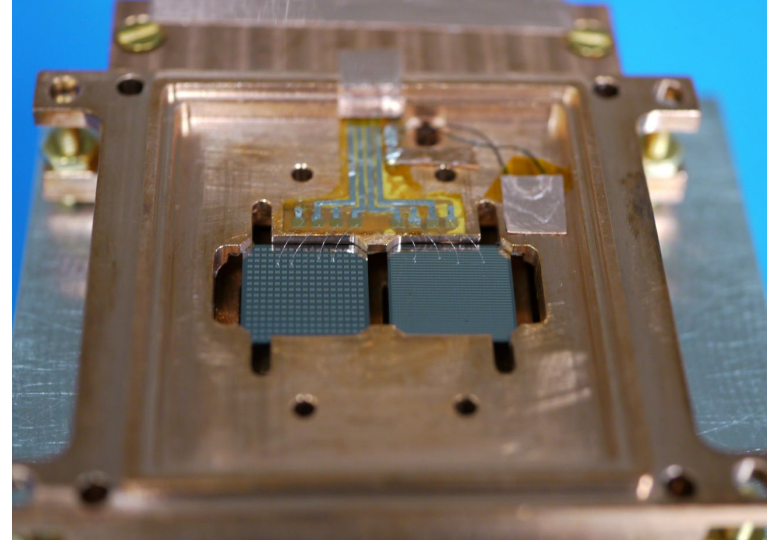
Run 3 – coincidence events

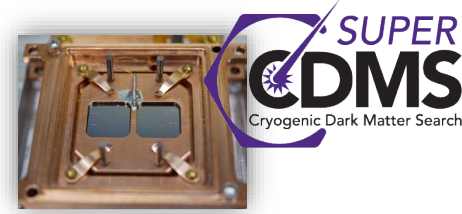
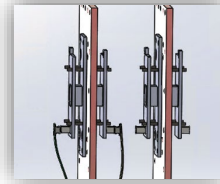
Confirmed external origin of the burst events



Run 4 – new detector holder

- the PCB was replaced by a copper holder in a light-tight copper box
- a tinned flex cable is used for electrical contact
- 4 closely-packed HVeV detectors to veto coincident events
- 4 spring mechanisms applying ~ 125 grams each





- Burst events detection and study
- Hypothesis: originated by SiO₂ in the detector holder (PCB)

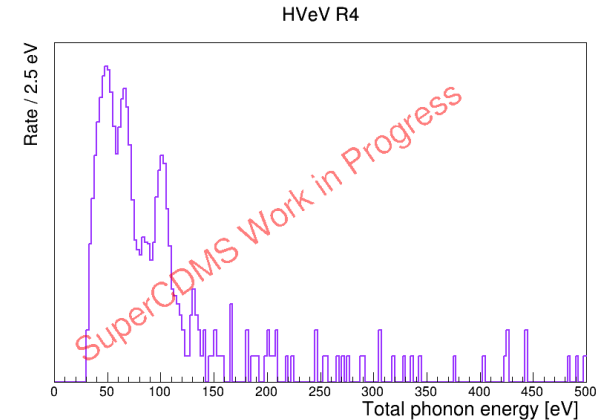
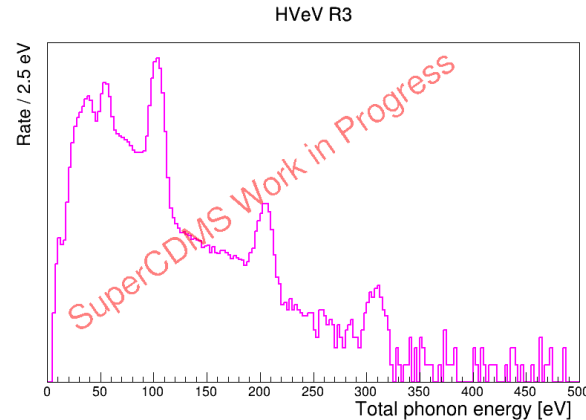
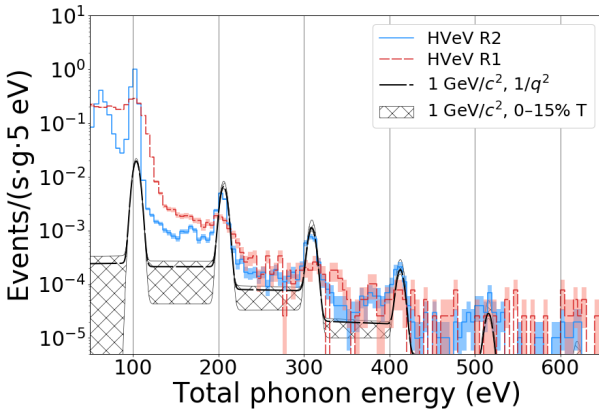
- Coincidence measurement
- Confirmed external origin of this background and its reduction with coincidence cut

- Removed PCB from the detector holder
- Elimination of the quantized background above 1 eh peak

HVeV R2

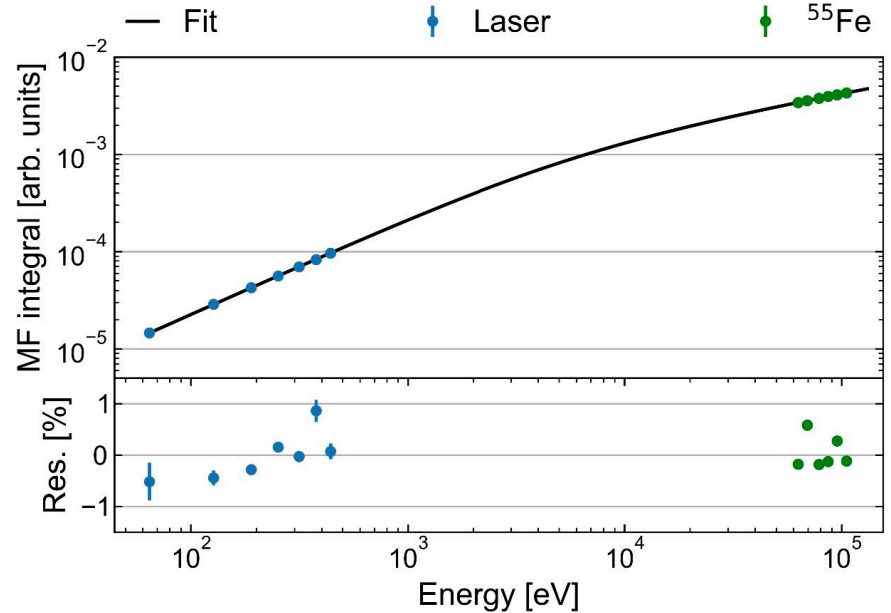
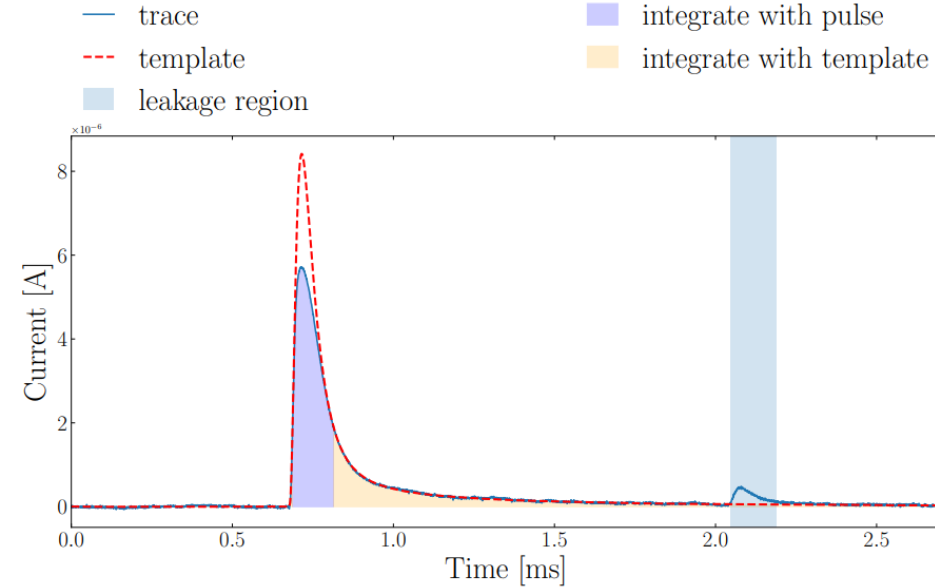
HVeV R3

HVeV R4



Extra ...

0VeV energy reconstruction/calibration



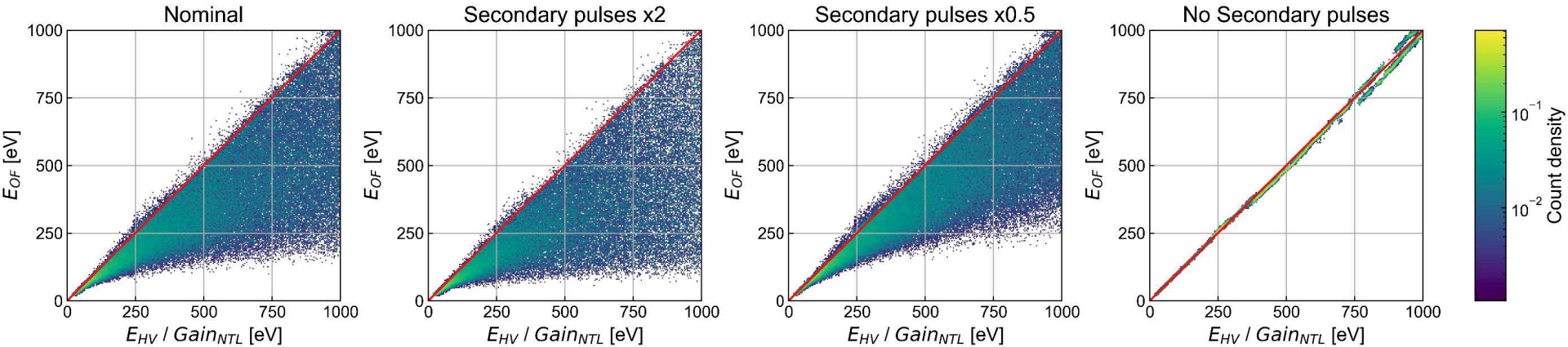
$$E = \begin{cases} E_{OF}, & E_{OF} < 600 \text{ eV} \\ (1 - k)E_{OF} + kE_{MF}, & 600 \text{ eV} \leq E_{OF} \leq 800 \text{ eV} \\ E_{MF}, & 800 \text{ eV} < E_{OF}. \end{cases}$$

$$k = \frac{E_{OF} - 600}{200}$$

R. Ren *et al.*, Phys. Rev. D 104, 032010, 2021

M. F. Albakry *et al.*, Phys. Rev. D 105, 112006, 2022

OF-MF response matrices



M. F. Albakry *et al.*, Phys. Rev. D 105, 112006, 2022

Calorimetric technique

